

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/736,344	<b>Applicant(s)/Patent under Reexamination</b> CHEN, YEN-CHUNG T.
	<b>Examiner</b> Khanh V. Nguyen	<b>Art Unit</b> 2817

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Search History Printout		9/14/2005	NKV